

GLOSSARY OF TECHNICAL TERMS

This glossary contains certain technical terms used in this document in connection with us and our business. Such terms and their meaning may not correspond to standard industry definitions or usage.

“ADC”	auto defect classification, an AI-driven visual inspection solution designed to automate defect detection and classification in manufacturing processes
“AI”	artificial intelligence
“AMHS”	automated material handling system, the integrated, computer-controlled solutions that automatically transport, store, and manage materials throughout a facility
“APS”	advanced planning and scheduling, an intelligent system that optimizes production schedules and resources
“AUTO3”	the third iteration or version of an automated system or technology in semiconductor industry, indicating advancements or improvements over previous versions
“BC”	block control, an intelligent manufacturing collaboration platform built on industrial IoT technology
“BI”	business intelligence, the combination of technologies, strategies, and methodologies used to collect, analyze, and present data to help organizations make better, data-driven decisions
“CIM”	computer integrated manufacturing, the manufacturing approach of using computers to control the entire production process
“CP”	chip probing (also known as wafer probing), a critical step in the semiconductor manufacturing process, situated between wafer fabrication and chip packaging, which is primarily used to verify the electrical characteristics and functionality of unpackaged chip units (Die) at the wafer level
“CTF”	cluster tool framework, a software platform designed for semiconductor equipment, providing equipment manufacturers with high-efficiency, flexible, and scalable software solutions
“DC”	data collection platform, an intelligent platform that gathers and integrates data from various sources
“EAP”	equipment automation program, a system designed to enhance the management of production processes by connecting directly with equipment
“EDA”	engineering data analysis, a system that analyzes engineering data to support decision-making

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“EHM”	equipment health management, a platform that integrates equipment process parameters into a unified data analytics framework
“ERP”	enterprise resource planning, an integrated software system that helps businesses manage and streamline core processes like supply chain and sales by consolidating data into a single, central database
“FDC”	fault detection and classification, an intelligent equipment management platform to monitor the stability of critical equipment parameters and classify faults in real-time through data collection, statistical analysis, and AI-driven modeling
“FVTPL”	fair value through profit or loss
“GEM”	generic equipment model, a standardized digital template that allows manufacturing equipment to be monitored and controlled by a factory host system
“GloryIGI”	glory industrial general intelligence, a software product that drives holistic intelligent transformation by unifying knowledge management, industry data assets, and comprehensive system interoperability which spans from the initial stages of production to the final output, enabling enterprises to optimize critical workflows from process engineering to decision intelligence
“GW”	gigawatt, a unit of power, one GW equals to 1,000,000,000 watt
“iEQ”	Equipment Communication Convert Module, product name of our self-developed solution to provide equipment data exchange services for enterprises in the pan-semiconductor industry
“IMSS”	intelligent manufacturing software solutions, the integrated platforms that connect machines, processes, and data to automate production, monitor performance in real time, and optimize decision-making across the entire manufacturing process
“Industry 4.0”	the fourth industrial revolution, which is characterized by the integration of digital technology into manufacturing processes to create smart factories and supply chains that are highly automated, data-interconnected, and responsive to real-time data for improved efficiency and productivity
“IoT”	internet of things, a network of interconnected devices, vehicles, appliances, and other physical objects that are embedded with sensors, software, and network connectivity
“J2EE”	Java 2 platform enterprise edition, a set of specifications for developing and deploying scalable, multi-tier enterprise applications
“KVM”	keyboard, video and mouse, a hardware solution based on IP network, consisting of components such as hosts and network interfaces, which is primarily used for server cluster management and industrial control

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“LCD”	liquid-crystal display, a thin, flat electronic display that uses liquid crystals and polarizers to control light and create images
“LED”	light emitting diode
“LOFA”	light off factory assistant, a smart control digital platform that integrates a suite of technologies, including remote centralized control, AI, and industrial vision, which enables automatic adjustment of lens magnification, precise identification of defect locations, and remote automated repair operations controlled via the remote control management
“MCS”	material control system, an intelligent logistics control platform that integrates heterogeneous material handling equipment across brands and types through unified protocols
“MES”	manufacturing execution system, a system tailored for the semiconductor and pan-semiconductor industries, offering functions such as production scheduling, material management, equipment management, and quality management
“OHT”	overhead hoist transport, an automated material handling system that uses ceiling-mounted rail-guided vehicles to transport material within semiconductor fabrication factories
“PCA”	principal component analysis, an algorithm that transforms a data set into a set of orthogonal components, which capture the maximum variance in the data
“PCB”	printed circuit board, a component in electronics that provides a stable base and conductive pathways to mechanically support and electrically connect electronic components
“PCC”	process control center, a centralized hub that monitors and manages all production parameters in real time to maintain optimal process conditions
“PDS”	process design & simulation, a simulation and correction tool designed to optimize semiconductor manufacturing processes
“PLC”	programmable logic controller, an industrial computer used to automate and control manufacturing processes
“QMS”	quality management system, an integrated digital platform to standardize and automate quality control processes across pan-semiconductor industries
“R&D”	research and development
“RCM”	remote control management, a hardware-software integrated solution designed to address the needs of manufacturing industries, including reducing labor costs, improving production efficiency, and enhancing product quality

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“RMS”	recipe management system, a management platform to standardize and automate the control of product parameters in semiconductor and manufacturing
“RPA”	robotic process automation, a software solution designed to deliver business automation which spans from the initial stages of production to the final output by leveraging intelligent technologies to “replace human labor” in repetitive, low-value, and rule-based workflows
“RTD”	real-time dispatching, a data-driven approach that ensures timely and efficient dispatch of materials and products
“SECS”	semiconductor equipment communication standard, a standard that specifies the message formats for data exchange used for automating and controlling semiconductor manufacturing equipment
“SEMI”	semiconductor equipment and materials international, the international organization that develops and maintains the standard in the semiconductor industry
“SPC”	statistical process control, the statistical methods that control and improve process quality
“TMS”	test management system, a system that manages testing processes and results
“VM”	virtual measurement, an AI-driven software solution designed to predict product characteristics (e.g., film thickness, impedance, line width) by integrating equipment and process parameters with statistical and machine learning models
“YMS”	yield management system, an analytics platform to optimize production yield and quality control in the pan-semiconductor industries